

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band**DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B**

Communication System: CDMA Cellular band; Frequency: 824.7 MHz; Duty Cycle: 1:1.04

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA;
- Measurement SW: DAS4, V4.5 Build 19;

E Scan -L-ch (Backlight on)/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 58.1 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3
54.8	54.7	44.9
Grid 4	Grid 5	Grid 6
57.1	57.0	47.8
Grid 7	Grid 8	Grid 9
51.0	51.1	43.3

Grid 1	Grid 2	Grid 3
55.9	55.8	45.8
Grid 4	Grid 5	Grid 6
58.3	58.1	48.8
Grid 7	Grid 8	Grid 9
52.0	52.1	44.1

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 57.1V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band**DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B**

Communication System: CDMA Cellular band; Frequency: 836.49 MHz; Duty Cycle: 1:1.04

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA;
- Measurement SW: DAS4, V4.5 Build 19;

E Scan -M-ch (Backlight on)/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

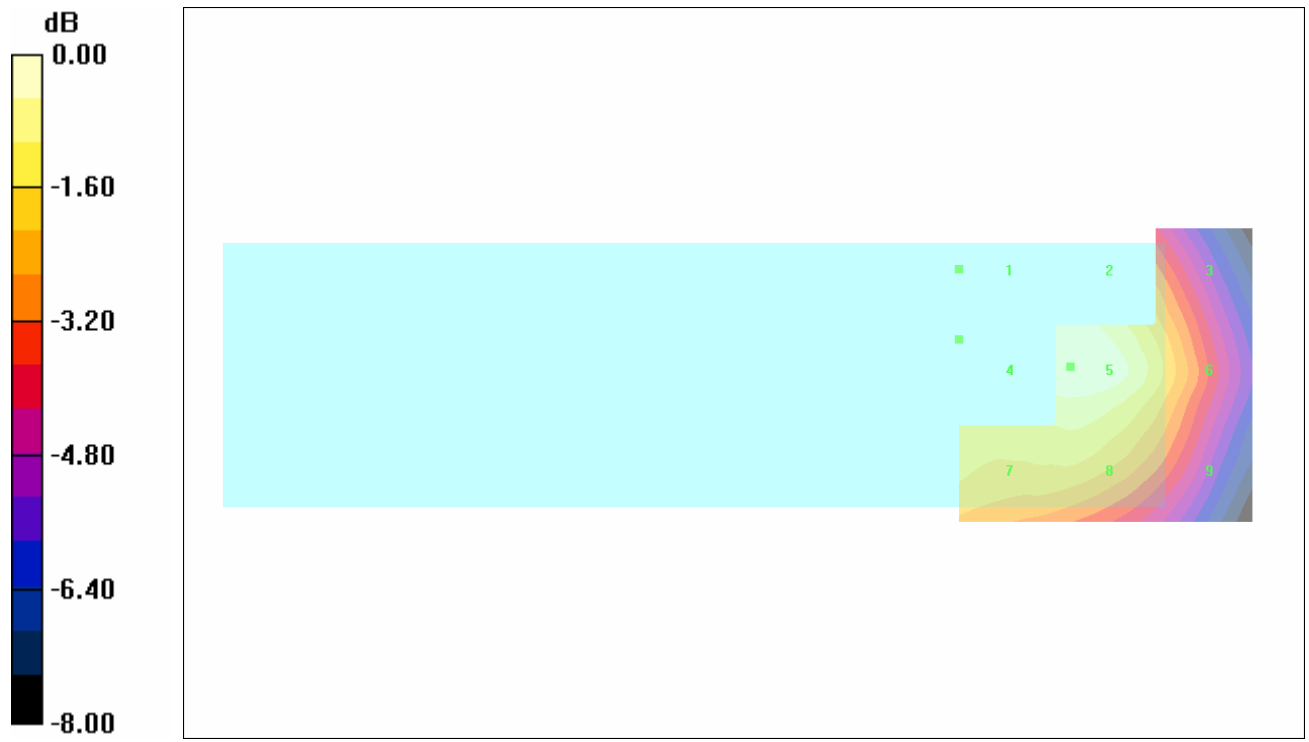
Maximum value of Total field (slot averaged) = 68.1 V/m

Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
64.0	64.1	53.3	65.3	65.3	54.4
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
66.7	66.8	57.4	68.0	68.1	58.6
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
59.1	59.6	51.6	60.3	60.8	52.6

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 66.8V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band**DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B**

Communication System: CDMA Cellular band; Frequency: 848.31 MHz; Duty Cycle: 1:1.04

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DASYS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA;
- Measurement SW: DASYS4, V4.5 Build 19;

E Scan -H-ch (Backlight on)/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

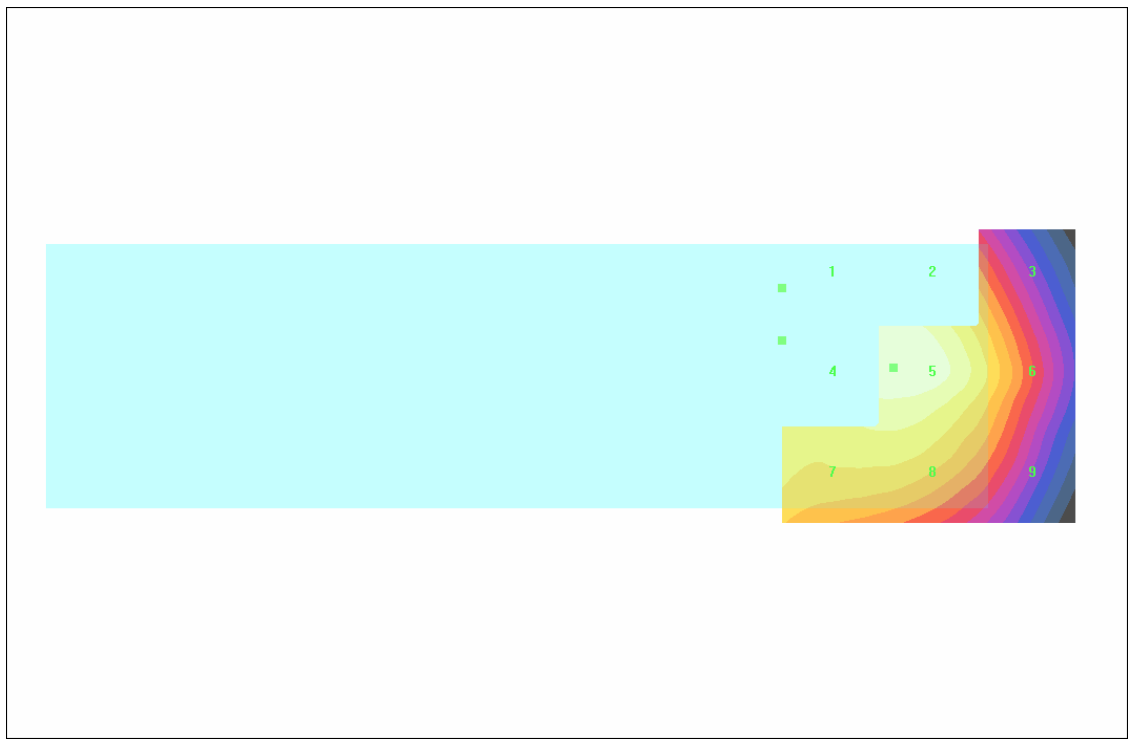
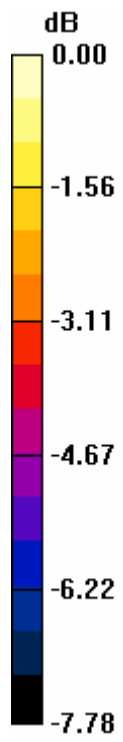
Maximum value of Total field (slot averaged) = 63.1 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
59.3	59.4	49.9	60.5	60.6	50.9
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
61.8	61.9	53.6	63.1	63.1	54.6
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
55.3	55.4	48.5	56.4	56.5	49.4

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 61.9V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band**DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B**

Communication System: CDMA Cellular band; Frequency: 824.7 MHz; Duty Cycle: 1:1.04

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA;
- Measurement SW: DAS4, V4.5 Build 19;

E Scan -L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

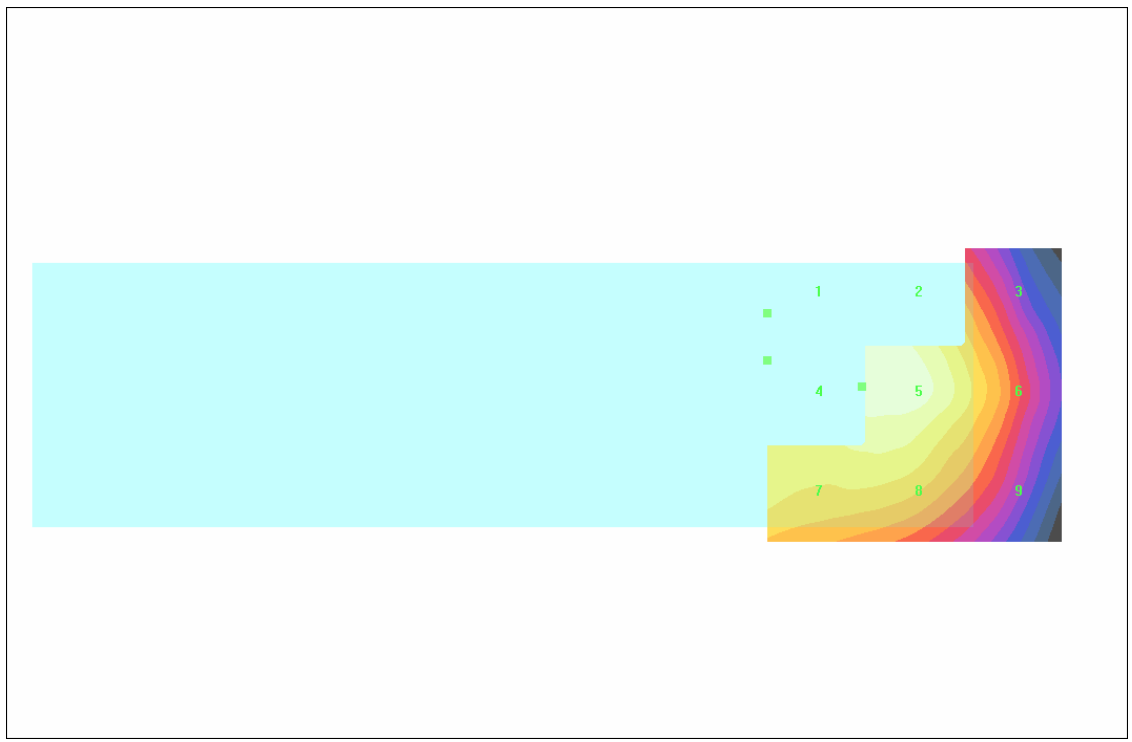
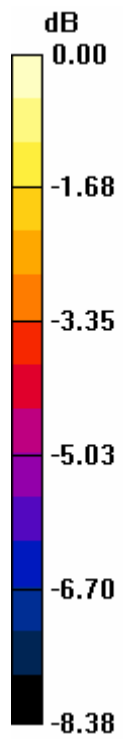
Maximum value of Total field (slot averaged) = 61.2 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 57.3	Grid 2 57.4	Grid 3 47.6	Grid 1 58.4	Grid 2 58.6	Grid 3 48.5
Grid 4 60.0	Grid 5 60.0	Grid 6 50.9	Grid 4 61.2	Grid 5 61.2	Grid 6 51.9
Grid 7 53.3	Grid 8 53.5	Grid 9 45.9	Grid 7 54.3	Grid 8 54.5	Grid 9 46.8

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 60.0V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band**DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B**

Communication System: CDMA Cellular band; Frequency: 836.49 MHz; Duty Cycle: 1:1.04

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA;
- Measurement SW: DAS4, V4.5 Build 19;

E Scan -M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 68.8 V/m

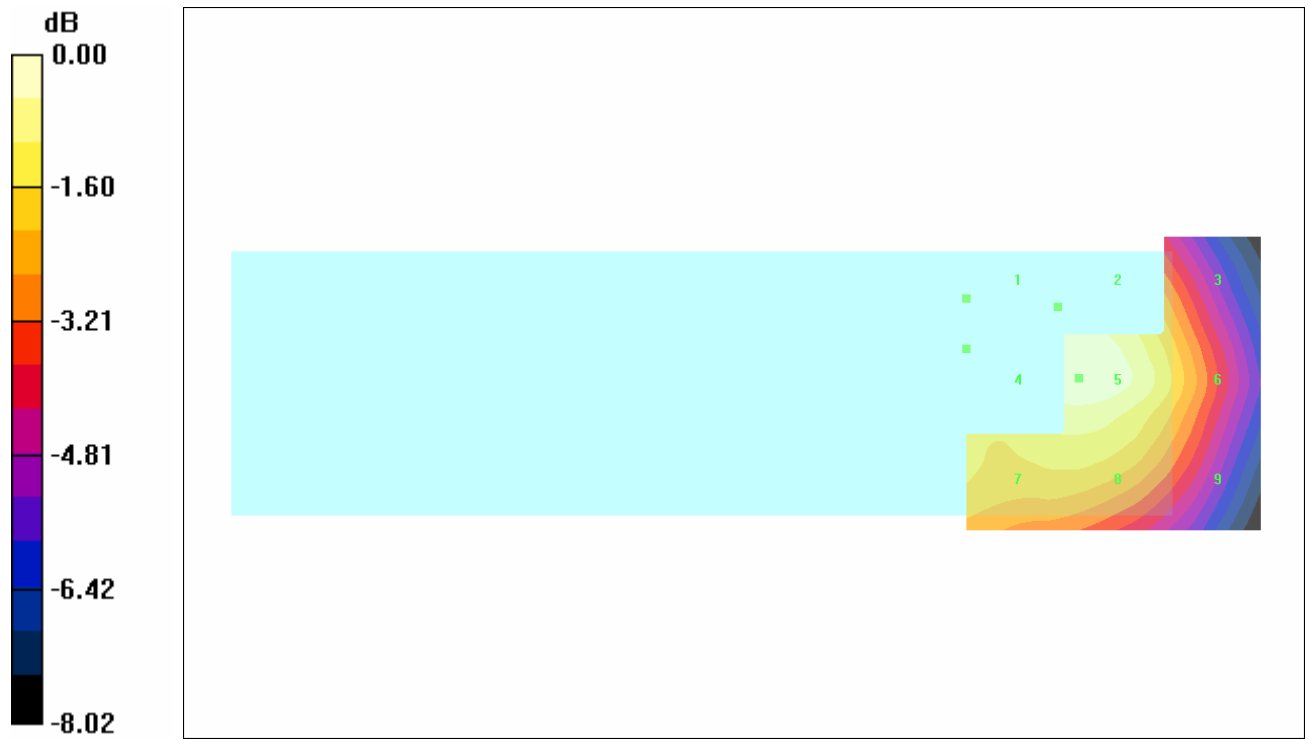
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3
64.2	64.7	54.2
Grid 4	Grid 5	Grid 6
67.2	67.5	57.9
Grid 7	Grid 8	Grid 9
59.8	59.8	52.1

Grid 1	Grid 2	Grid 3
65.5	65.9	55.3
Grid 4	Grid 5	Grid 6
68.6	68.8	59.0
Grid 7	Grid 8	Grid 9
60.9	61.0	53.1

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 67.5V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device Cell band**DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B**

Communication System: CDMA Cellular band; Frequency: 848.31 MHz; Duty Cycle: 1:1.04

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DASYS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA;
- Measurement SW: DASYS4, V4.5 Build 19;

E Scan -H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 64.5 V/m

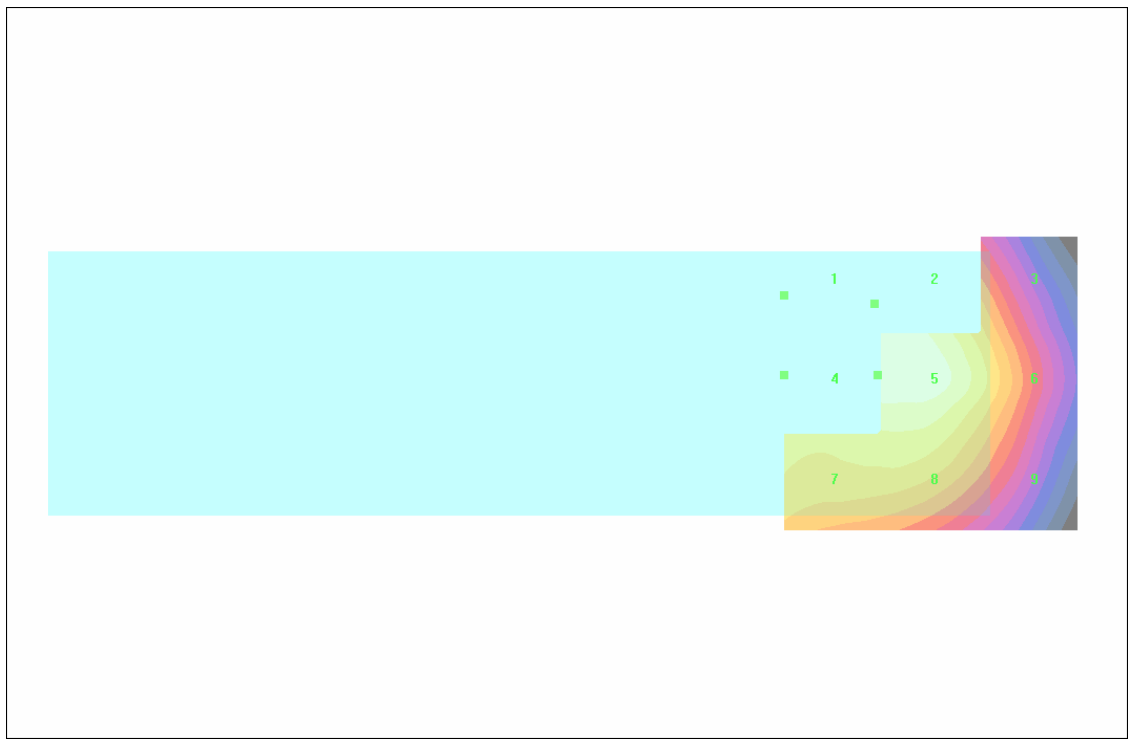
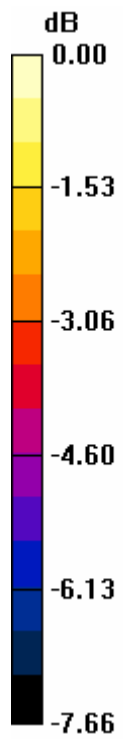
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2	Grid 3
60.0	60.4	50.8
Grid 4	Grid 5	Grid 6
63.3	63.2	54.5
Grid 7	Grid 8	Grid 9
56.0	56.2	48.9

Grid 1	Grid 2	Grid 3
61.2	61.6	51.8
Grid 4	Grid 5	Grid 6
64.5	64.5	55.6
Grid 7	Grid 8	Grid 9
57.1	57.3	49.9

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 63.3V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device_Backlight on_072205

DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B

Communication System: CDMA PCS Band; Frequency: 1851.25 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

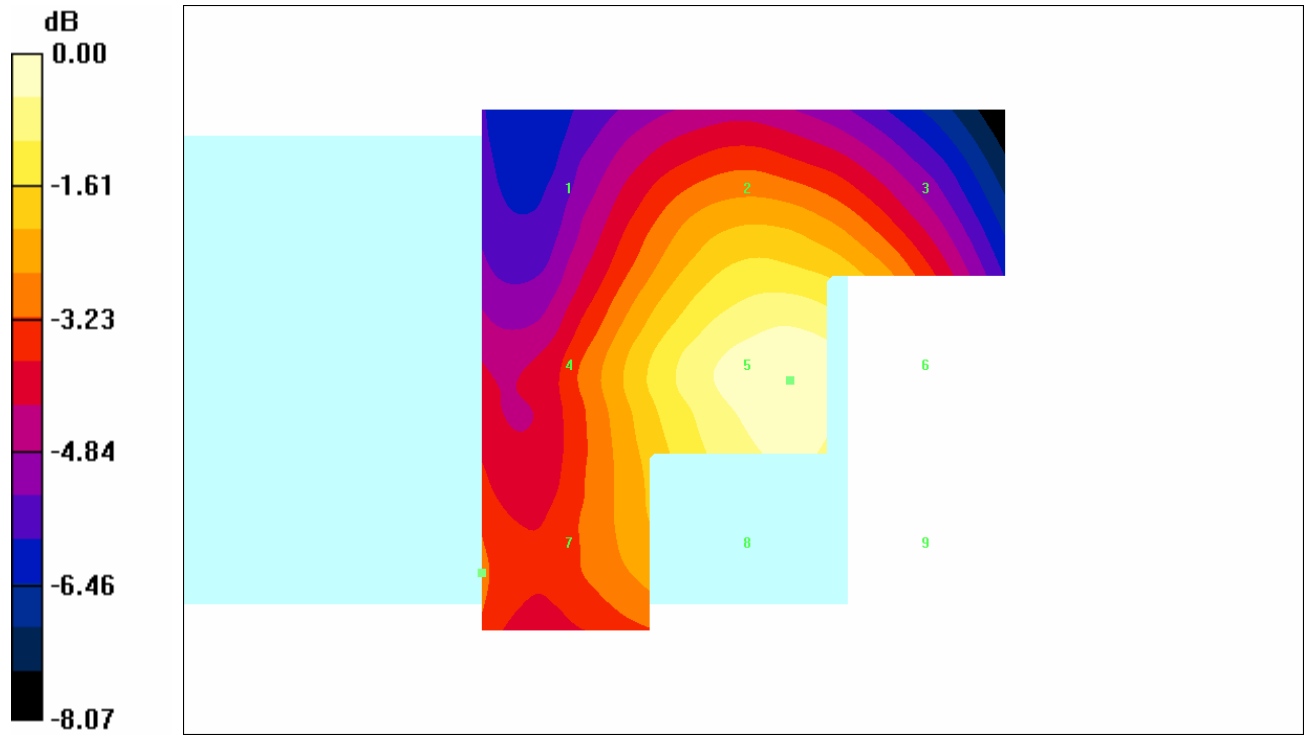
Maximum value of Total field (slot averaged) = 35.4 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 25.9	Grid 2 30.4	Grid 3 29.2	Grid 1 25.9	Grid 2 30.4	Grid 3 29.2
Grid 4 29.6	Grid 5 35.4	Grid 6 34.4	Grid 4 29.6	Grid 5 35.4	Grid 6 34.4
Grid 7 28.2	Grid 8 33.7	Grid 9 32.6	Grid 7 28.2	Grid 8 33.7	Grid 9 32.6

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 35.4V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device_Backlight on_072205

DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B

Communication System: CDMA PCS Band; Frequency: 1880 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

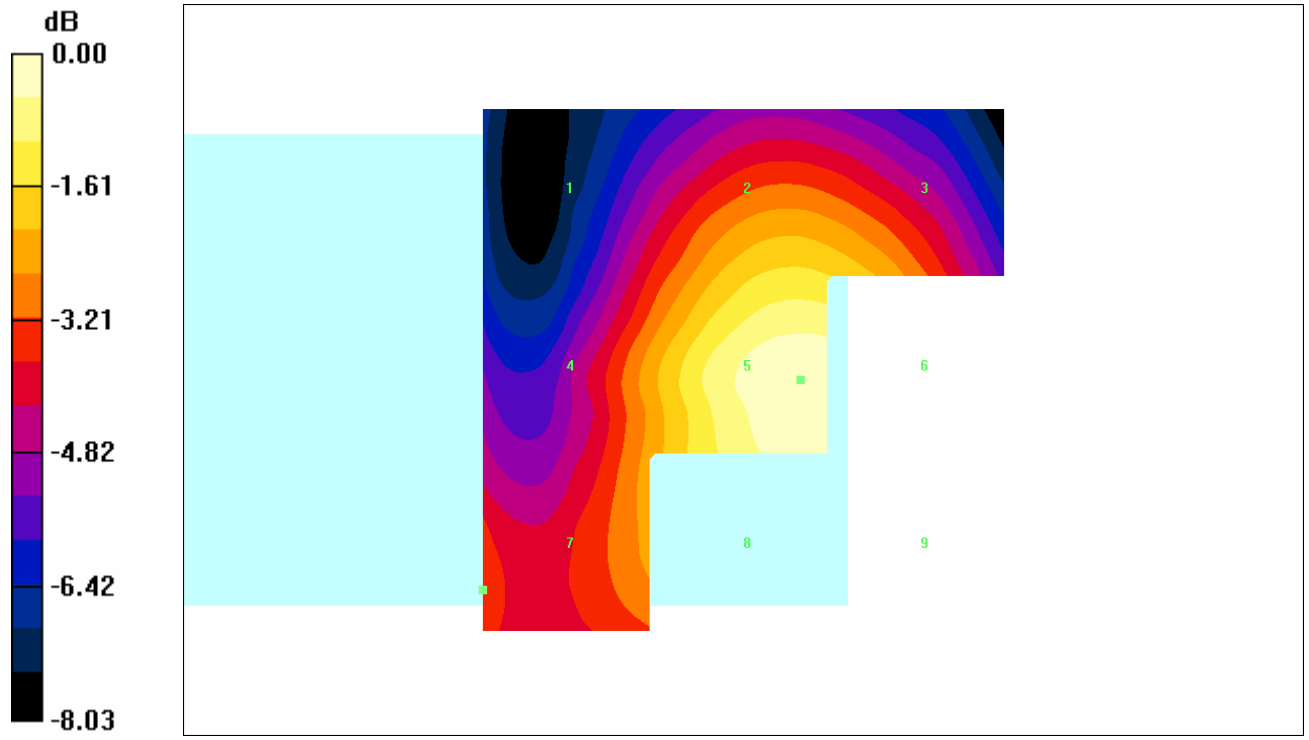
E Scan - M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 39.6 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged)			E in V/m (Slot averaged)		
Grid 1 25.9	Grid 2 33.6	Grid 3 32.9	Grid 1 25.9	Grid 2 33.6	Grid 3 32.9
Grid 4 30.2	Grid 5 39.6	Grid 6 38.9	Grid 4 30.2	Grid 5 39.6	Grid 6 38.9
Grid 7 30.1	Grid 8 38.3	Grid 9 37.8	Grid 7 30.1	Grid 8 38.3	Grid 9 37.8

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



Test Laboratory: Compliance Certification Services

HAC_E_Device_Backlight on_072205

DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B

Communication System: CDMA PCS Band; Frequency: 1908.75 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

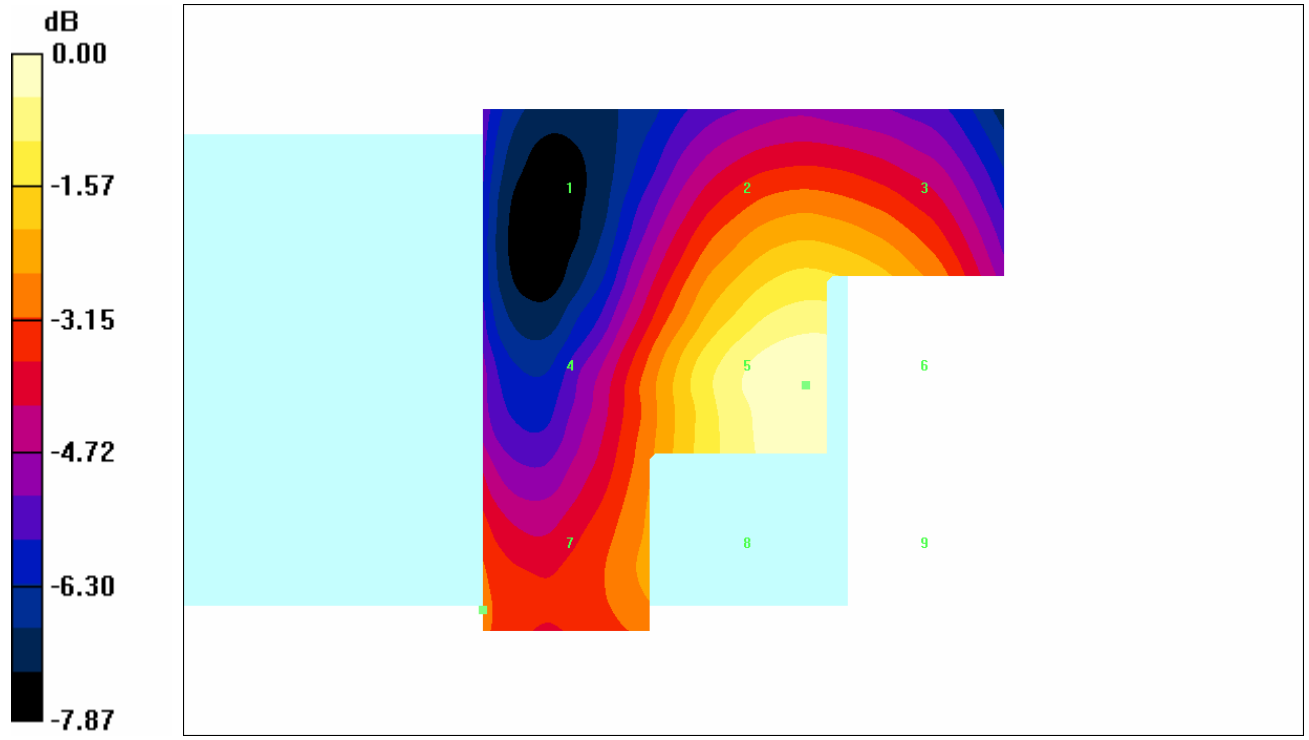
Maximum value of Total field (slot averaged) = 36.1 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 21.7	Grid 2 30.6	Grid 3 30.3	Grid 1 21.7	Grid 2 30.6	Grid 3 30.3
Grid 4 26.4	Grid 5 36.1	Grid 6 35.9	Grid 4 26.4	Grid 5 36.1	Grid 6 35.9
Grid 7 27.4	Grid 8 35.3	Grid 9 34.9	Grid 7 27.4	Grid 8 35.3	Grid 9 34.9

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 36.1V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device_Backlight off_072205

DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B

Communication System: CDMA PCS Band; Frequency: 1851.25 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

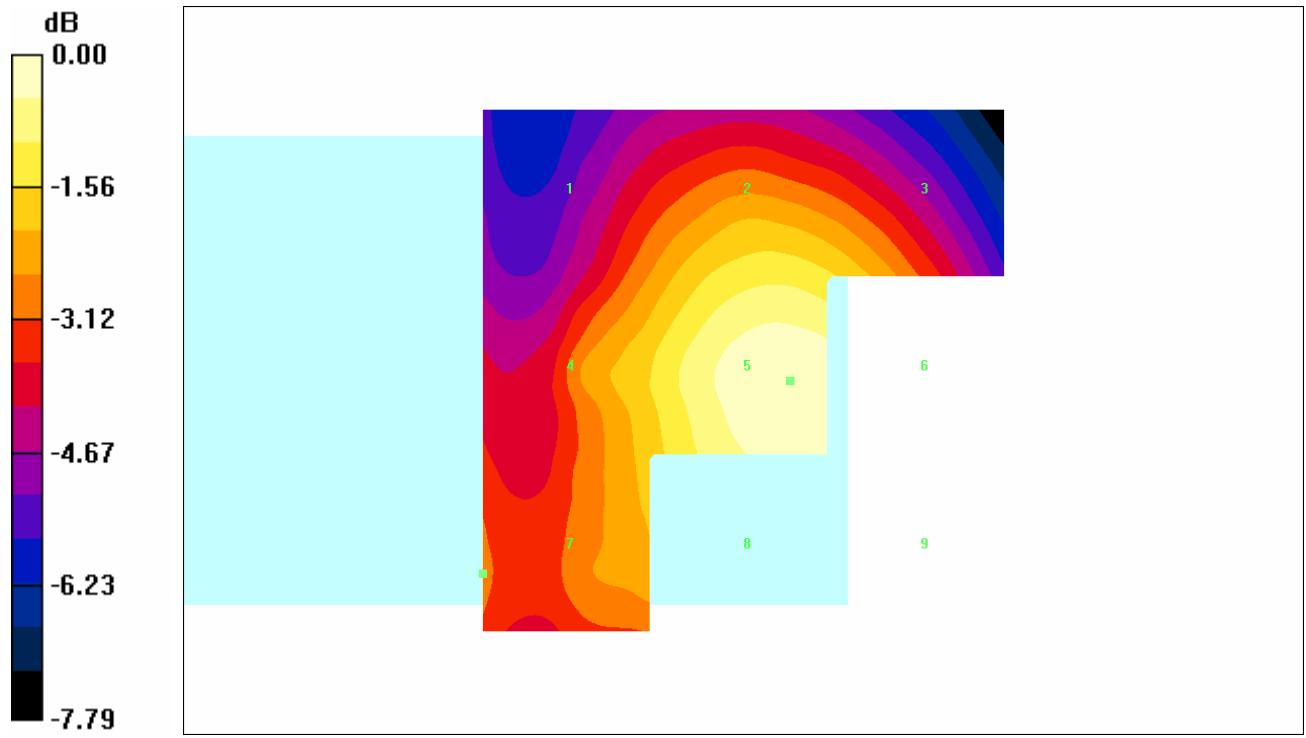
E Scan - L-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 33.2 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged)			E in V/m (Slot averaged)		
Grid 1 24.8	Grid 2 29.1	Grid 3 28.0	Grid 1 24.8	Grid 2 29.1	Grid 3 28.0
Grid 4 27.8	Grid 5 33.2	Grid 6 32.3	Grid 4 27.8	Grid 5 33.2	Grid 6 32.3
Grid 7 26.9	Grid 8 31.9	Grid 9 31.2	Grid 7 26.9	Grid 8 31.9	Grid 9 31.2

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



Test Laboratory: Compliance Certification Services

HAC_E_Device_Backlight off_072205

DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B

Communication System: CDMA PCS Band; Frequency: 1880 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

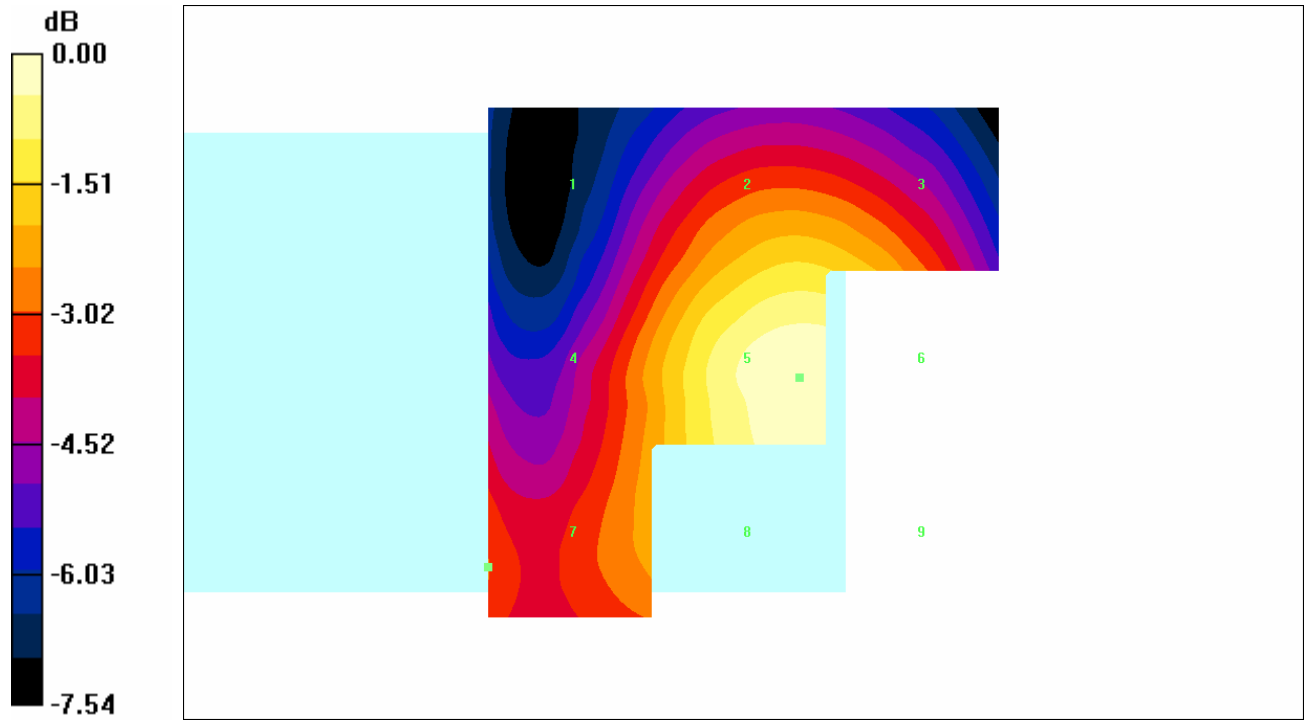
E Scan - M-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

Maximum value of Total field (slot averaged) = 37.0 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged)			E in V/m (Slot averaged)		
Grid 1 24.5	Grid 2 31.7	Grid 3 31.2	Grid 1 24.5	Grid 2 31.7	Grid 3 31.2
Grid 4 28.5	Grid 5 37.0	Grid 6 36.5	Grid 4 28.5	Grid 5 37.0	Grid 6 36.5
Grid 7 28.8	Grid 8 35.9	Grid 9 35.7	Grid 7 28.8	Grid 8 35.9	Grid 9 35.7

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 37.0V/m

Test Laboratory: Compliance Certification Services

HAC_E_Device_Backlight off_072205

DUT: Kyocera; Type: KX9A; Serial: 20-N7092-01B

Communication System: CDMA PCS Band; Frequency: 1908.75 MHz; Duty Cycle: 1:1

Medium parameters used: $\sigma = 0$ mho/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: E Device Section

Measurement Standard: DAS4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 - SN2339; ConvF(1, 1, 1); Calibrated: 3/11/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE3 Sn500; Calibrated: 2/7/2005
- Phantom: HAC Test Arch; Type: SD HAC P01 BA; Serial: 1011
- Measurement SW: DAS4, V4.5 Build 19; Postprocessing SW: SEMCAD, V1.8 Build 146

E Scan - H-ch/Hearing Aid Compatibility Test (101x101x1): Measurement grid: dx=5mm, dy=5mm

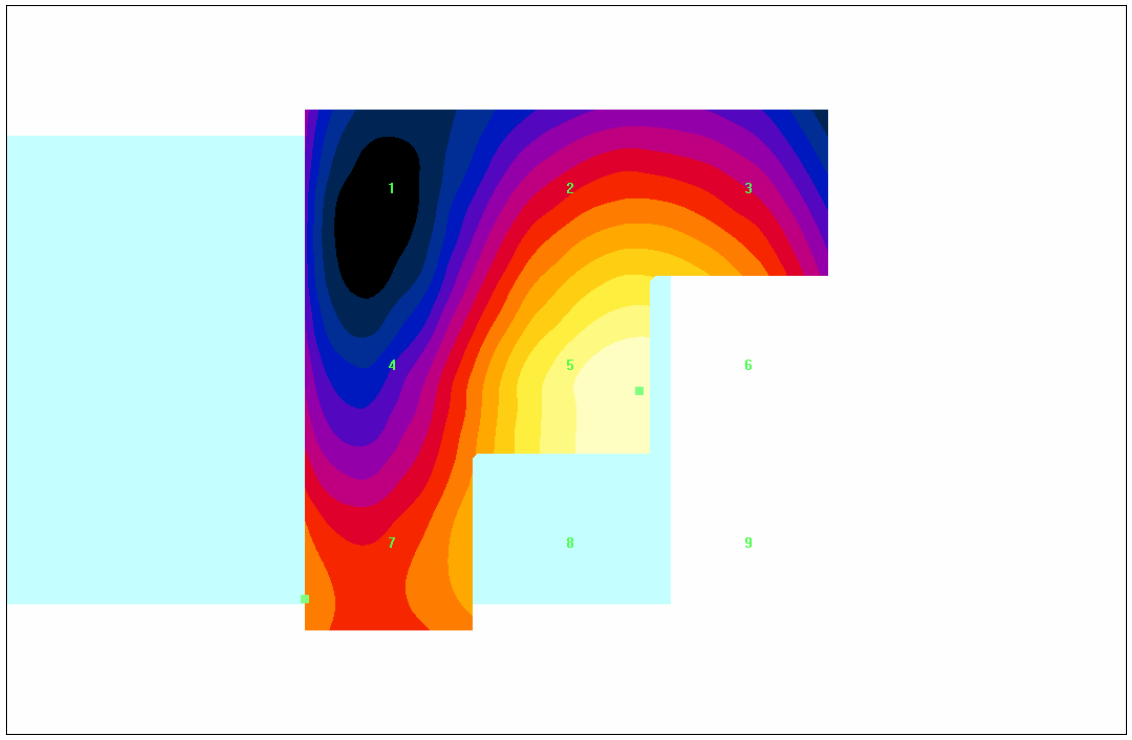
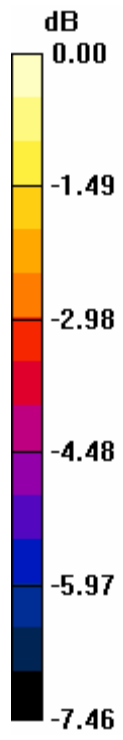
Maximum value of Total field (slot averaged) = 33.8 V/m

Hearing Aid Near-Field Category: M4 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1 20.3	Grid 2 28.6	Grid 3 28.4	Grid 1 20.3	Grid 2 28.6	Grid 3 28.4
Grid 4 25.2	Grid 5 33.8	Grid 6 33.7	Grid 4 25.2	Grid 5 33.8	Grid 6 33.7
Grid 7 26.6	Grid 8 33.3	Grid 9 33.1	Grid 7 26.6	Grid 8 33.3	Grid 9 33.1

Category	AWF (dB)	Limits for E-Field Emissions (V/m)	Limits for H-Field Emissions (A/m)
M1	0	199.5 - 354.8	0.6 - 1.07
	-5	149.6 - 266.1	0.45 - 0.8
M2	0	112.2 - 199.5	0.34 - 0.6
	-5	84.1 - 149.6	0.25 - 0.45
M3	0	63.1 - 112.2	0.19 - 0.34
	-5	47.3 - 84.1	0.15 - 0.25
M4	0	<63.1	<0.19
	-5	<47.3	<0.15



0 dB = 33.8V/m